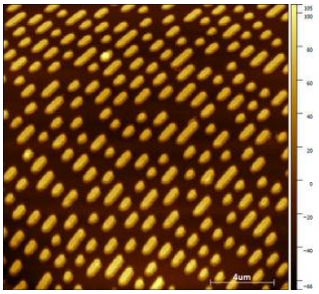
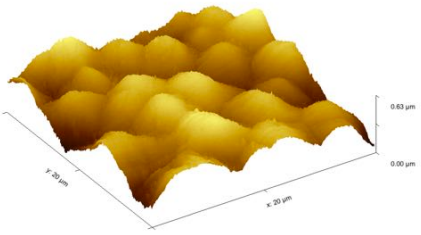
Workshop: **Introduction to Atomic Force Microscopy**

Thursday, October 4th, 2018 from 2 – 4 PM
Ruttan Room (Room 321) Otto Maass Chemistry Building
McGill University





Atomic force microscopy (AFM) is one of the most widely used techniques for measurement at the nanoscale. AFM uses a very small probe tip that scans across the surface and physically 'feels' the topography of a sample, kind of like a record player. The interaction between the tip and the surface is measured, which means that, unlike optical or electron microscopy, AFM generates a 3-dimensional reconstruction of the surface. Typical applications include investigation of sample topography, surface roughness, particle counting, grain size, and phase imaging, which can reveal differences in mechanical, adhesive, and frictional properties of surfaces.

In this brief workshop on atomic force microscopy you will learn about:

- The principle of operation of AFM
- Single-chip AFMs and how they work
- How to operate an nGauge AFM (live demonstration)
- Processing AFM images in open source software (Gwyddion)
- How to use AFM in your research

Are you interested in having your sample tested with the nGauge AFM during the workshop or while ICSPI is on campus at McGill? Get in touch with David Morris, Director of Operations at ICSPI, at david@icspicorp.com before Thursday, September 27, 2018

Coffee and light refreshments will be served.

Seating is limited. Reserve your spot at https://www.icspicorp.com/mcgillchem

CQMF QCAM

MC2 MCGILL CHEMISTRY CHARACTERIZATION

MI MICROSCOPY AND IMAGING

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